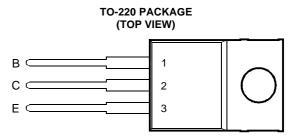
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- 80 W at 25°C Case Temperature
- **7 A Continuous Collector Current**
- **10 A Peak Collector Current** •
- Maximum  $V_{CE(sat)}$  of 2 V at  $I_C = 5 A$
- I<sub>CEX(sus)</sub> 7 A at rated V<sub>(BR)CEO</sub>



Pin 2 is in electrical contact with the mounting base.

MDTRACA

#### absolute maximum ratings at 25°C case temperature (unless otherwise noted)

RATING	SYMBOL	VALUE	UNIT	
	TIP150		300	
Collector-base voltage ( $I_E = 0$ )	TIP151	V <sub>CBO</sub>	350	V
	TIP152		400	
	TIP150	0	300	
Collector-emitter voltage $(I_B = 0)$	TIP151	V <sub>CEO</sub>	350	V
	TIP152		400	
Emitter-base voltage	A REAL	V <sub>EBO</sub>	8	V
Continuous collector current	3	I <sub>C</sub>	7	A
Peak collector current (see Note 1)	011	ГСМ	10	A
Continuous base current	I <sub>B</sub>	1.5	A	
Continuous device dissipation at (or below) 25°C case temperature (see Note 2)			80	W
Continuous device dissipation at (or below) 25°C free air temperature (see Not	e 3)	P <sub>tot</sub>	2	W
Operating junction temperature range		Тj	-65 to +150	°C
Storage temperature range	T <sub>stg</sub>	-65 to +150	°C	
Lead temperature 3.2 mm from case for 10 seconds			260	°C

NOTES: 1. This value applies for t<sub>p</sub> ≤ 5 ms, duty cycle ≤ 10%.
2. Derate linearly to 150°C case temperature at the rate of 0.64 W/°C.
3. Derate linearly to 150°C free air temperature at the rate of 16 mW/°C.



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#### electrical characteristics at 25°C case temperature

PARAMETER		TEST CONDITIONS			MIN	TYP	MAX	UNIT
V <sub>(BR)CBO</sub>	Collector-base breakdown voltage			TIP150	300			
		I <sub>C</sub> = 1 mA	$I_E = 0$	TIP151	350			V
	broakaown vokago			TIP152	400			
V <sub>(BR)CEO</sub>	Collector-emitter breakdown voltage			TIP150	300			
		$I_{\rm C} = 10  \rm mA$	$I_B = 0$	TIP151	350			V
		(see Note 4)		TIP152	400			
I <sub>CEO</sub>	Collector-emitter cut-off current	V <sub>CE</sub> = 300 V	I <sub>B</sub> = 0	TIP150			250	μA
		V <sub>CE</sub> = 350 V	$I_B = 0$	TIP151			250	
		V <sub>CE</sub> = 400 V	$I_B = 0$	TIP152			250	
I <sub>CEX(sus)</sub>	Collector-emitter sustaining current	V <sub>CLAMP</sub> = V <sub>(BR)CE</sub>	0		7			А
I <sub>EBO</sub>	Emitter cut-off current	V <sub>EB</sub> = 8 V	$I_{\rm C} = 0$				15	mA
h <sub>FE</sub>	Forward current transfer ratio	V <sub>CE</sub> = 5 V	I <sub>C</sub> = 2.5 A		150			
		$V_{CE} = 5 V$	I <sub>C</sub> = 5 A	(see Notes 4 and 5)	50			
		$V_{CE} = 5 V$	I <sub>C</sub> = 7 A		15			
	Collector-emitter saturation voltage	I <sub>B</sub> = 10 mA	I <sub>C</sub> = 1 A				1.5	
V <sub>CE(sat)</sub>		I <sub>B</sub> = 100 mA	I <sub>C</sub> = 2 A	(see Notes 4 and 5)			1.5	V
( )		I <sub>B</sub> = 250 mA	I <sub>C</sub> = 5 A				2	
V	Base-emitter	I <sub>B</sub> = 100 mA	I <sub>C</sub> = 2 A	(see Notes 4 and 5)			2.2	V
V <sub>BE(sat)</sub>	saturation voltage	I <sub>B</sub> = 250 mA	I <sub>C</sub> = 5 A	(see Notes 4 and 5)			2.3	v
$V_{\text{EC}}$	Parallel diode forward voltage	I <sub>E</sub> = 7 A	I <sub>B</sub> = 0	(see Notes 4 and 5)			3.5	V
h <sub>fe</sub>	Small signal forward current transfer ratio	V <sub>CE</sub> = 5 V	l <sub>C</sub> = 0.5 A	f = 1 kHz	200			
h <sub>fe</sub>	Small signal forward current transfer ratio	$V_{CE} = 5 V$	I <sub>C</sub> = 0.5 A	f = 1 MHz	10			
C <sub>ob</sub>	Output capacitance	$V_{CB} = 10 V$	$l_{\rm E} = 0$	f = 1 MHz			100	pF

NOTES: 4. These parameters must be measured using pulse techniques,  $t_p = 300 \ \mu$ s, duty cycle  $\leq 2\%$ .

5. These parameters must be measured using voltage-sensing contacts, separate from the current carrying contacts.

### thermal characteristics

PARAMETER			ТҮР	MAX	UNIT
$R_{\theta JC}$	Junction to case thermal resistance			1.56	°C/W
$R_{\thetaJA}$	Junction to free air thermal resistance			62.5	°C/W
$C_{\theta C}$	Thermal capacitance of case		0.9		J/°C

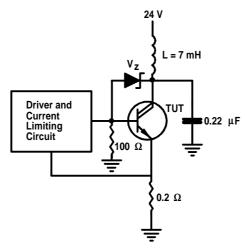
### inductive-load-switching characteristics at 25°C case temperature

	PARAMETER	TEST CONDITIONS <sup>†</sup>			MIN	TYP	MAX	UNIT
t <sub>sv</sub>	Voltage storage time				3.9		μs	
t <sub>si</sub>	Current storage time					4.7		μs
t <sub>rv</sub>	Voltage transition time		I <sub>B(on)</sub> = 250 mA	$R_{BE} = 47 \ \Omega$		1.2		μs
t <sub>ti</sub>	Current transition time				1.2		μs	
t <sub>xo</sub>	Cross-over time				2.0		μs	

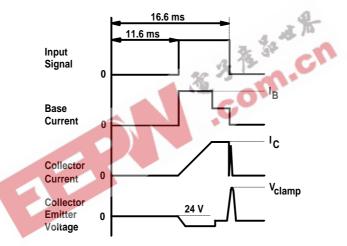
<sup>†</sup> Voltage and current values shown are nominal; exact values vary slightly with transistor parameters.

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#### PARAMETER MEASUREMENT INFORMATION









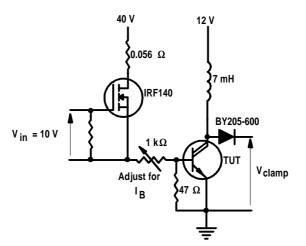
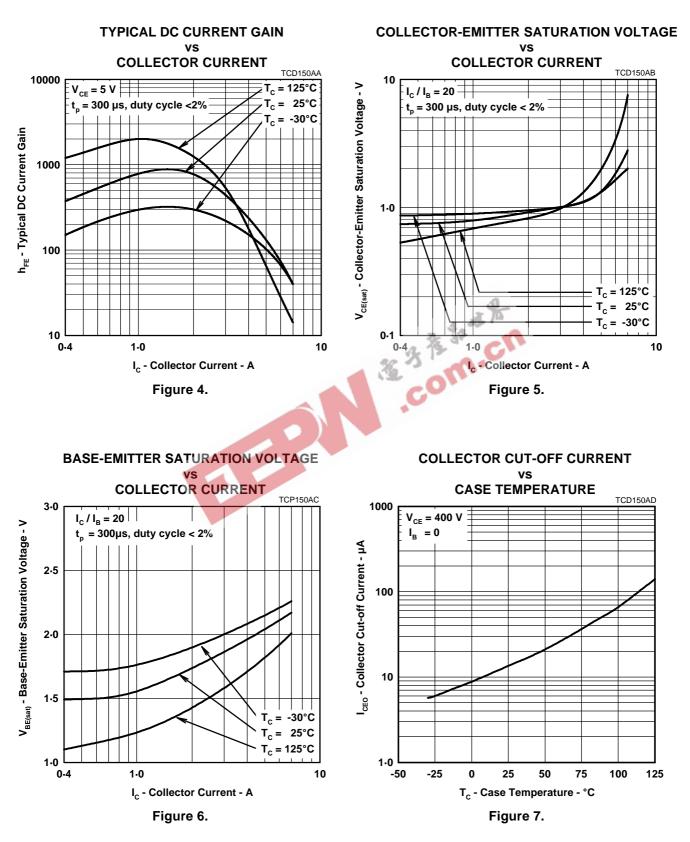


Figure 3. Switching Test Circuit



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### **TYPICAL CHARACTERISTICS**

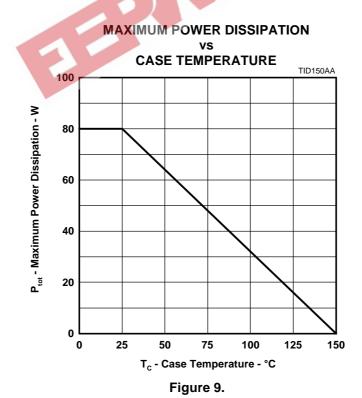


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#### **MAXIMUM FORWARD-BIAS** SAFE OPERATING AREA SAD150AA 100 10 I<sub>c</sub> - Collector Current - A 1.0 0.1 = 0.1 ms 1 ms = TIP150 5 ms t<sub>p</sub> = TIP151 **DC** Operation TIP152 0.01 1.0 10 100 1000 V<sub>ce</sub> - Collector-Emitter Voltage - V 4 Figure 8.

### MAXIMUM SAFE OPERATING REGIONS

**THERMAL INFORMATION** 





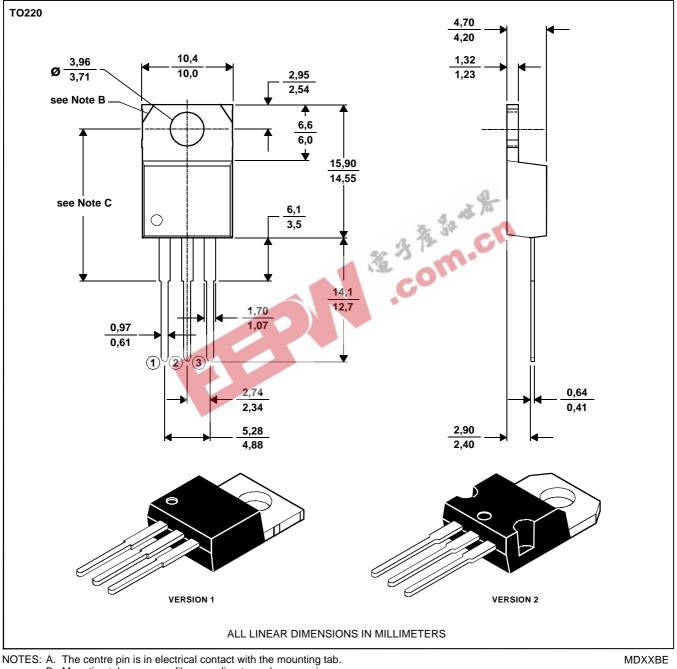
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### **MECHANICAL DATA**

### TO-220

#### 3-pin plastic flange-mount package

This single-in-line package consists of a circuit mounted on a lead frame and encapsulated within a plastic compound. The compound will withstand soldering temperature with no deformation, and circuit performance characteristics will remain stable when operated in high humidity conditions. Leads require no additional cleaning or processing when used in soldered assembly.



B. Mounting tab corner profile according to package version.

C. Typical fixing hole centre stand off height according to package version.

Version 1, 18.0 mm. Version 2, 17.6 mm.

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